

<b>Notice of References Cited</b>	Application/Control No. 10/762,526	Applicant(s)/Patent Under Reexamination CHOI ET AL.	
	Examiner Jeffrie R. Lund	Art Unit 1763	Page 1 of 2

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	Examiner Jeffrie R. Lund	Art Unit 1763	Page 2 of 2

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